1. Electrical Specification

1-1 Test condition

Varistor voltage In = 1 mA DC Leakage current Vdc = 10V DC

Maximum clamping voltage Ic = 1 A

Rated peak single pulse transient current $8/20 \mu s$ waveform, +/- each 1 time induce

Capacitance 10/1000 μ s waveform Insulation resistance after reflow soldering f = 1MHz, Vrms = 0.5 V

Soldering paste : Tamura (Japan) RMA-20-21L

Stencil : SUS, 120 μ m thickness

Reflow soldering condition Pad size : 0.5 (Width) x 0.6 (Length)

0.5 (Distance between pads)

Soldering profile : 260 ± 5 °C, 5 sec.

1-2 Electrical specification

Maximum allowable continuous DC voltage 10			
trigger voltage / Varistor voltage / breakdown voltage	18-22	V	
Maximum clamping voltage	45	V	Maximum
Rated peak single pulse transient current	1	Α	Maximum
Nonlinearity coefficient	> 12		
Leakage current at continuous DC voltage	< 0.1	μ A	
Response time	< 0.5	ns	
Varistor voltage temperature coefficient	< 0.05	%/℃	
Capacitance measured at 1MHz 33		pF	Typical
Capacitance tolerance	-50 to +50	%	
Insulation resistance after reflow soldering on PCB	> 10	$M\Omega$	
Operating ambient temperature	-55 to +125	${\mathbb C}$	
Storage temperature	-55 to +125	$^{\circ}$ C	

1-3 Reliability testing procedures

Reliability parameter	Test	Test methods and remarks	Test requirement
Pulse current capability	lmax 8/20 μs	IEC 1051-1, Test 4.5. 10 pulses in the same direction at 2 pulses per minute at maximum peak current	d Vn /Vn ≤ 10% no visible damage
Electrostatic discharge capability	ESD C=150 pF, R=330 Ω	IEC 1000-4-2 Each 10 times in positive/negative direction in 10 sec at 8KV contact discharge (Level 4) d Vn /Vn ≤ no visible da	
Environmenta I reliability	Thermal shock	IEC 68-2-14 Condition for 1 cycle Step 1 : Min40°C, 30±3 min. Step 2 : Max. +125°C, 30±3 min. Number of cycles: 30 times	d Vn /Vn ≤ 5% no visible damage
	Low temperature	Harmser of cycles. 30 times	d Vn /Vn ≤ 5% no visible damage
	High temperature	IEC 68-2-2 Place the chip at 125 ± 5 °C for 1000 ± 24 hrs. Remove and place for 24 ± 2 hrs at room temp. condition, then measure	d Vn /Vn ≤ 5% no visible damage
	Heat resistance	IEC 68-2-3 Apply the rated voltage for $1000\pm48 hrs$ at $85\pm3\%$. Remove and place for $24\pm2 hrs$ at room temp. condition, then measure	d Vn /Vn ≤ 5% no visible damage
	Humidity resistance	IEC 68-2-30 Place the chip at $40\pm2\%$ and 90 to 95% humidity for 1000 ± 24 hrs. Remove and place for 24 ± 2 hrs at room temp. condition, then measure	d Vn /Vn ≤ 10% no visible damage
	Pressure cooker test	Place the chip at 2 atm, 120 °C, 85%RH for 60 hrs. Remove and place for 24 ± 2hrs at room temp. condition, then measure	d Vn /Vn ≤ 10% no visible damage
	Operating life	Apply the rated voltage for 1000 ± 48 hrs at $125 \pm 3^{\circ}$ C. Remove and place for 24 ± 2 hrs at room temp. condition, then measure	d Vn /Vn ≤ 10% no visible damage

Mechanical	Solderability	IEC 68-2-58	At least 95% of terminal
Reliability		Solder bath method, 230 \pm 5 $^{\circ}\mathrm{C}$, 2s	electrode is covered by new solder
	Resistance to	IEC 68-2-58	d Vn /Vn ≤ 5%
soldering heat	Solder bath method, 260 ± 5 °C, 10 ± 0.5 s, 270 ± 5 °C, 3 ± 0.5 s	no visible damage	
	Bending strength	IEC 68-2-21	$dVn /Vn \le 5\%$
		Warp:2mm, Speed:0.5mm/sec, Duration: 10sec. The measurement shall be made with board in the bent position	no visible damage
	Adhesive strength	IEC 68-2-22	Strength>10 N
		Applied force on SMD chip by fracture from PCB	no visible damage

2. Material Specification

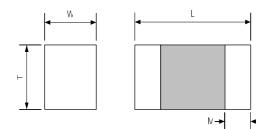
Body ZnO based ceramics

Internal electrode Silver – Palladium

External electrode Silver – Nickel – Tin

Thickness of Ni/Sn plating layer Nickel $> 1 \mu m$, Tin $> 2 \mu m$

3. Dimension Specification

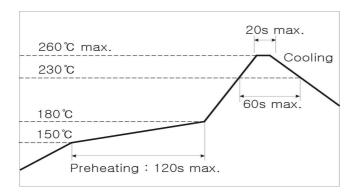


Size	L(mm)	W(mm)	T(mm)	M(mm)
0402	1.0 ± 0.10	0.5 ± 0.10	≤ 0.6	0.20 ± 0.10
0603	1.6±0.15	0.8 ± 0.15	≤ 0.9	0.35 ± 0.10

4. Soldering Recommendations

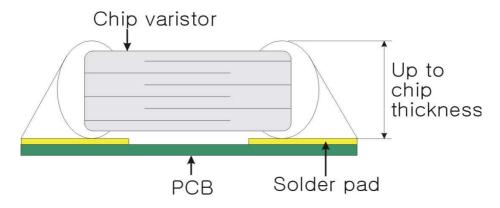
4-1 Soldering profile

4-1-1 Pb free solder paste



4-1-2 Repair soldering

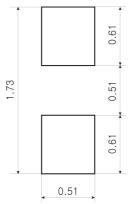
- Allowable time and temperature for making correction with a soldering iron : 350 \pm 10 $^{\circ}$ C, 3 sec.
- Optimum solder amount when corrections are made using a soldering iron



4-2 Soldering guidelines

- Our chip varistors are designed for reflow soldering only. Do not use flow soldering
- Use non-activated flux (CI content 0.2% max.)
- Follow the recommended soldering conditions to avoid varistor damage.

4-3 Solder pad layout



5. Storage condition

- Storage environment must be at an ambient temperature of 25~35 $\,^\circ\!\mathbb{C}\,$ and an ambient humidity of 40~60 $^\circ\!\!\!/$ RH
- Chip varistors can experience degradation of termination solderability when subjected to high temperature of humidity, or if exposed to sulfur or chlorine gases.
- Avoid mechanical shock (ex. Falling) to the chip varistor to prevent mechanical cracking inside of the ceramic dielectric due to its own weight.
- Use chips within 6 months.
 If 6 months of more have elapsed, check solderability before use.-

6. Description about package label

Type: MVR0402-100E330

MVR: Series name

0402 : Chip size -0402 (1.0 x 0.5 mm) size

100 : Maximum continuous working voltage – 10Vdc

E: Product function - E for ESD

330 : Capacitance value - means 33pF

Qunatity: 10,000 pcs

- Quantity of shipping chip varistor